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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Hiroshi SONOBE

Group Art Unit: 2133

Serial No.: 09/557,088

Examiner: Matthew C. Dooley

Filed: April 21, 2000

For: SEMICONDUCTOR INSPECTION METHOD

PRELIMINARY AMENDMENT

RECEIVED

MAR 19 2004

Technology Center 2100

Mail Stop RCE  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Sir:

Prior to further examination of the above-identified application, and subsequent to entry of the Amendment Under 37 CFR §1.116 filed on December 22, 2003, please amend the claims of this application:

03/18/2004 CNGUYEN 00000057 09557088

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